



PATENT APPLICATION

IN THE U.S. PATENT AND TRADEMARK OFFICE

October 19, 2005

Applicants: Takemi MUROGA et al

For: OXIDE SUPERCONDUCTING WIRE

Serial No.: 10/634 030

Group: 1754

Confirmation No.: 5287

Filed: August 4, 2003

Examiner: Cooke

Atty. Docket No.: Komatsu 291

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the provisions of Rules 1.97(e)(1) and 1.98, enclosed herewith is a copy of an Office Action dated August 17, 2005 and the cited references received in the counterpart Japanese foreign application, Form PTO-1449 and the references cited thereon. Further comment at this point in time should not be necessary.

I hereby certify that each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.

Further consideration is respectfully solicited.

Respectfully submitted,


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Encl: Copy of Japanese Office Action dated August 17, 2005
Form PTO-1449 and references cited thereon
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INFORMATION
DISCLOSURE
CITATION

Applicant: Nariaki ASANO et al
 Ser.No.: 10/516 166 Filed: November 24, 2004
 Conf. No.: 2915 Atty. Docket No.: OPS 663
 Group: 1755 Date: October 19, 2005

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant
	AA			
	AB			
	AC			
	AD			
	AE			
	AF			
	AG			
	AH			
	AI			
	AJ			
	AK			

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.	Country Code - Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Trans.
	AL	JP 2002-203439	07-19-2002	HONJO et al	Abstract
	AM	WO 00/22652	04-20-2000	KWON et al	Abstract
	AN	JP 2003-034527	02-07-2003	HONJO et al	Abstract
	AO	JP 11-086647	03-30-1999	HOSAKA et al	Abstract
	AP				

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	(Include Author, Title, Date, Pages, Etc.)
	AQ	
	AR	
EXAMINER SIGNATURE		DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.